

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL To Commissioner For Patents Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.	Application Number	10/591193
	Filing Date	
	First Named Inventor	AZIMANE, MOHAMED
	Group Art Unit	
	Examiner Name	d. mcMahon
	Atty. Docket Number	US04 0145 US3

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number No.-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Petentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
/D.M./	1	US- 6 115 836	09/05/2000	CHURCHILL ET AL.	
		US-			
		US-			
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Document Number (ctry ³ -no.-kind ⁵ , if known)	Publication Date MM-DD-YYYY	Name of Petentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
/D.M./	1	JP 2001 332099	04/03/2002	HITACHI LTD		
/D.M./	2	WO 02/103706	12/27/2002	TEMPLETON MARK ET AL.		
/D.M./	3	EP 0 867 887	09/30/1998	HASHIMOTO MASAHI ET AL.		

NON-PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No. ¹	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T ⁶
/D.M./	1	AZIMANE M ET AL: "NEW TEST METHODOLOGY FOR RESISTIVE OPEN DEFECT DETECTION IN MEMORY ADDRESS DECODERS"; VLSI TEST SYMPOSIUM 2004; PROCEEDINGS 22 ND IEEE NAPA VALLEY CA USA 25-29; APRIL 2004; PISCATAWAY NJ USA IEEE; PP 123-128.				

Examiner Signature	/Daniel F. McMahon/	Date Considered	08/20/2008
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.